



Optical Trapping

Guest Editor:

Dr. Mathieu L. Juan

Institute for Quantum Optics and
Quantum Information of the
Austrian Academy of Sciences, A-
6020 Innsbruck, Austria

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Message from the Guest Editor

Over the years, the optical trapping toolbox evolved from the simple manipulation to the accurate measurement and control of the position of trapped objects. The forces in the pico-Newton range, along the micrometer precision, provided by optical traps constitute a powerful tool to study various phenomena at the micron scale such as molecular physics and microrheology. Taking advantage of concepts from near-field optics, the capabilities of optical traps have been further extended to the nano-scale, offering also the possibility to integrate optical manipulation on-chip in order to develop integrated lab-on-a-chip platforms. In a completely different context, optical trapping recently received a lot of interest in the field of quantum opto-mechanics for its capacity to levitate resonators, providing a promising platform for the study of massive particles in the quantum regime. This Special Issue “Optical Trapping” aims at compiling some of the most recent work relying on the use of optical forces and their various application in physics.

Keywords

- Optical forces
- Near-field optics
- Optical levitation
- Optomechanics
- Microrheology
- Lab-on-a-chip
- Sensing





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Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo

Dipartimento di Fisica,
Politecnico di Milano, Piazza L.
da Vinci 32, 20133 Milano, Italy

Message from the Editor-in-Chief

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